TOSHIBA Transistor Silicon NPN Epitaxial Planar Type

2SC5085

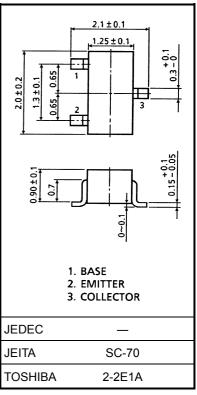
VHF~UHF Band Low Noise Amplifier Applications

Unit: mm

- Low noise figure, high gain.
- NF = 1.1dB, $|S_{21e}|^2 = 11dB$ (f = 1 GHz)

Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit	
Collector-base voltage	V_{CBO}	20	V	
Collector-emitter voltage	V _{CEO}	12	V	
Emitter-base voltage	V _{EBO}	3	٧	
Base current	Ι _Β	40	mA	
Collector current	I _C	80	mA	
Collector power dissipation	P _C	100	mW	
Junction temperature	Tj	125	°C	
Storage temperature range	T _{stg}	-55~125	°C	



Weight: 0.006 g (typ.)

Microwave Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit			
Transition frequency	f _T	V _{CE} = 10 V, I _C = 20 mA	5	7	_	GHz			
Insertion gain	S _{21e} ² (1)) V _{CE} = 10 V, I _C = 20 mA, f = 500 MHz —			_	dB			
Insertion gain	S _{21e} ² (2)	V _{CE} = 10 V, I _C = 20 mA, f = 1 GHz	7.5	11	_	_ ub			
Noise figure	NF (1)	$V_{CE} = 10 \text{ V}, I_{C} = 5 \text{ mA}, f = 500 \text{ MHz}$	_	1	_	dB			
Noise ligure	NF (2)	$V_{CE} = 10 \text{ V}, I_{C} = 5 \text{ mA}, f = 1 \text{ GHz}$		1.1	2	uБ			

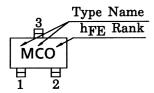
Electrical Characteristics (Ta = 25°C)

Characteristics Symbol		Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I _{CBO}	$V_{CB} = 10 \text{ V}, I_{E} = 0$	_	_	1	μА
Emitter cut-off current	I _{EBO}	I _{EBO} V _{EB} = 1 V, I _C = 0		_	1	μА
DC current gain	h _{FE} (Note 1)	V _{CE} = 10 V, I _C = 20 mA	80	_	240	
Output capacitance	C _{ob}	V _{CB} = 10 V, I _F = 0, f = 1 MHz (Note 2)	_	1.0	_	pF
Reverse transfer capacitance	C _{re}	$\frac{1}{2}$ VCB - 10 V, $\frac{1}{12}$ - 0, $\frac{1}{12}$ 1 IVIHZ (NOTE 2)		0.65	1.15	pF

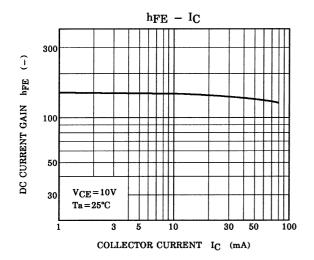
Note 1: hFE classification O: 80~160, Y: 120~240

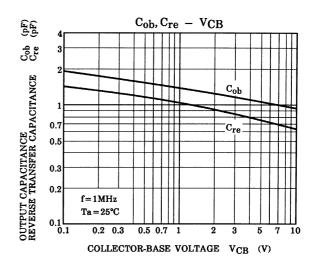
Note 2: C_{re} is measured by 3 terminal method with capacitance bridge.

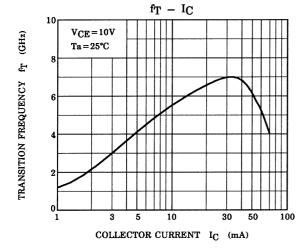
Marking

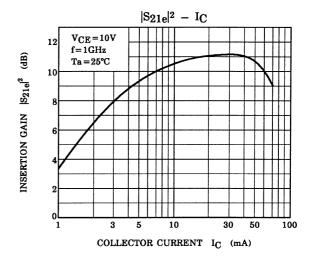


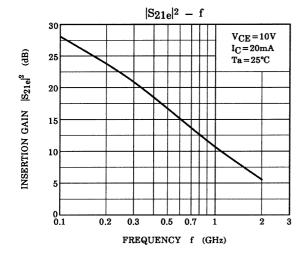
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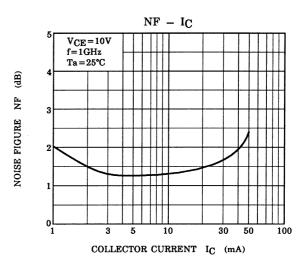




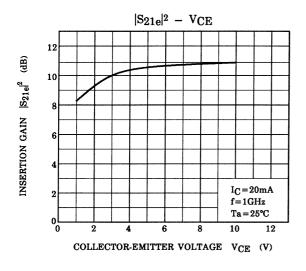


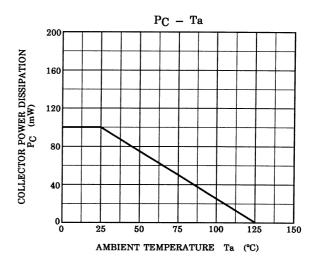






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S-Parameter $Z_O = 50 \Omega$, Ta = 25°C

$V_{\text{CE}} = 10 \ \text{V}, \ I_{\text{C}} = 5 \ \text{mA}$

Frequency	y S11		S21		S12		S22	
(MHz)	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.672	-73.0	9.460	128.6	0.052	53.6	0.707	-31.3
400	0.498	-115.9	6.268	105.9	0.068	46.8	0.513	-36.2
600	0.443	-141.7	4.554	93.3	0.078	49.0	0.437	-36.6
800	0.426	-158.7	3.556	84.5	0.088	53.2	0.401	-36.8
1000	0.422	-171.9	2.948	77.5	0.099	57.9	0.383	-38.3
1200	0.428	177.5	2.526	71.1	0.113	62.7	0.373	-40.6
1400	0.437	168.3	2.240	65.5	0.133	65.8	0.367	-43.9
1600	0.449	159.9	1.997	60.1	0.152	67.6	0.362	-48.2
1800	0.464	153.1	1.821	55.0	0.171	68.7	0.358	-52.8
2000	0.485	146.7	1.686	50.9	0.195	70.6	0.350	-57.6

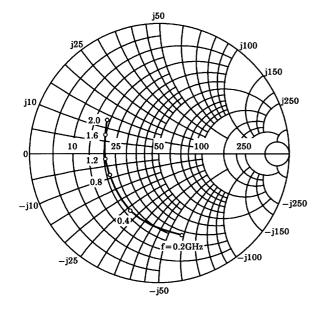
$V_{CE} = 10 \text{ V}, I_C = 20 \text{ mA}$

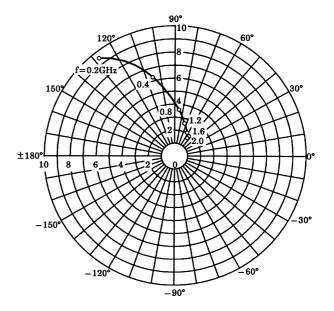
Frequency	S11		S21		S12		S22	
(MHz)	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
200	0.392	-116.4	16.247	109.3	0.034	59.7	0.420	-43.7
400	0.329	-152.1	8.775	94.5	0.054	66.0	0.280	-38.4
600	0.321	-170.6	6.018	86.3	0.075	69.5	0.244	-33.7
800	0.321	177.5	4.598	80.2	0.097	70.7	0.231	-31.7
1000	0.324	167.9	3.767	74.8	0.119	71.2	0.225	-31.3
1200	0.332	160.3	3.191	70.0	0.142	71.3	0.225	-32.7
1400	0.341	153.5	2.812	65.2	0.168	70.0	0.225	-36.2
1600	0.352	146.6	2.502	60.7	0.190	68.4	0.222	-40.3
1800	0.362	142.2	2.264	56.5	0.212	66.8	0.217	-44.9
2000	0.379	137.7	2.092	52.8	0.236	66.3	0.212	-49.4

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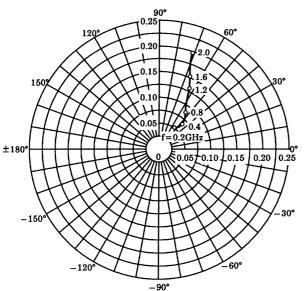
 $\begin{array}{l} S_{11e} \\ V_{CE} = 10V \\ I_{C} = 5mA \\ Ta = 25^{\circ}C \\ (UNIT:\Omega) \end{array}$







 $\begin{array}{l} S_{12e} \\ V_{CE} = 10V \\ I_{C} = 5 mA \\ Ta = 25 ^{\circ}C \end{array}$



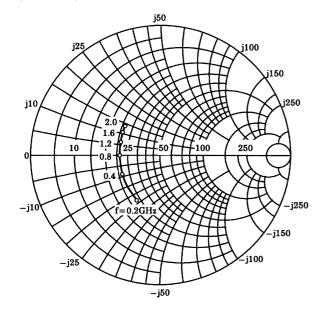
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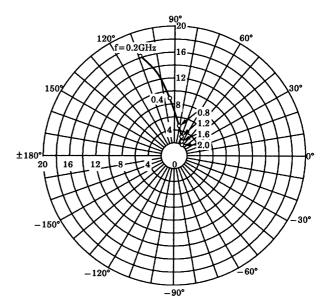
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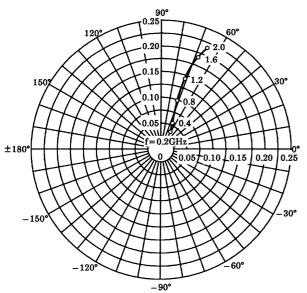
 $\begin{array}{l} S_{11e} \\ V_{CE}\!=\!10V \\ I_{C}\!=\!20mA \\ Ta\!=\!25^{\circ}\!C \\ (UNIT:\Omega) \end{array}$







 $\begin{array}{l} S_{12e} \\ V_{CE} = 10V \\ I_{C} = 20 mA \\ Ta = 25 ^{\circ}C \end{array}$



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